

# **Notice of References Cited**

Application/Control No.

10/809,130

Applicant(s)/Patent Under  
Reexamination  
SEO ET AL.

Examiner

C. Melissa Koslow

Art Unit

1793

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	V	Takaeda et al, "Modification of sol-gel-derived amorphous Al <sub>2</sub> O <sub>3</sub> thin films by F <sub>2</sub> excimer laser irradiation at ambient temperature", J. Mater. Res., Vol 16, No. 4, 4/2001, pp.1003-1009.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.